Machine Learning Technologies for Big Data Analytics

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Message from the Guest Editors

Big Data has become essential as numerous organizations deal with massive amounts of specific information, which can contain useful information about problems such as national intelligence, cybersecurity, biology, fraud detection, marketing, astronomy, and medical informatics. Several promising machine learning techniques can be used for Big Data analytics including representation learning, deep learning, distributed and parallel learning, transfer learning, active learning, and kernel-based learning. In addition, Big Data analytics demands new and sophisticated algorithms based on machine learning techniques to treat data in real-time with high accuracy and productivity. The goal of this special issue is to discuss several critical issues related to learning from massive amounts of data and highlight current research endeavors and the challenges to big data, as well as shared recent advances in this research area. We solicit new contributions that have a strong emphasis on Machine Learning for Big Data Analytics.

Special issue

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Message from the Editor-in-Chief

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